

INFORMATION DISCLOSUREDocket No.: 860-011850-US(PAR)/
20020565

Serial No.: 10/500,981

O I P
**CITATION FORM FOR
PATENT APPLICATION**
MAR 11 2005 (FORM PTO-1449)
(Substitute)

Applicant(s): ROSENFELDT

Filing Date: 07/02/2004

Group:

U.S. PATENTS

Initials	Patent Number	Issue Date	Name	Class	Sub-class	Filing date

U.S. PATENT PUBLICATIONS

Initials	Publication No.	Pub. Date	Name	Class	Sub-class	Filing Date

FOREIGN PATENT DOCUMENTS

Initials	Document Number	Date	Country	Name	Translation? Yes/No/n/a
/SAT/	EP 1 113 250 B1	2/5/03	Europe	Agilent Technologies, Inc.	N/A
/SAT/	EP 1 014 033 A2	6/28/00	Europe	Anritsu Corporation	N/A
/SAT/	EP 1 202 038 A1	5/2/02	Europe	Agilent Technologies, Inc.	N/A
/SAT/	JP2000097856	4/7/00	Japan	Nippon Telegr & Teleph Corp.	YES

OTHER DOCUMENTS (Title, Author, Date, Pages, Etc., if known)

/SAT/	K. Takada, K. Okamoto: "Frequency-domain measurement of phase error distribution in narrow-channel arrayed-waveguide grating", Electronics Letters, Vol. 36, No. 2, January 20, 2000 pp. 160-161

Examiner's Signature: /Samuel A. Turner/

Date Considered: 08/27/2007

Initial if reference was considered, whether or not citation is in conformance with MPEP. Mark through citation if not considered.
Include a copy of this citation form with your next correspondence to the Applicant(s).

Customer No.: 2512